

<b>Notice of References Cited</b>	Application/Control No. 10/815,842	Applicant(s)/Patent Under Reexamination SU ET AL.	
	Examiner Wesley D. Markham	Art Unit 1762	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2004/0211271	10-2004	Han et al.	073/866.5
*	B	US-6,616,497	09-2003	Choi et al.	445/24
*	C	US-6,911,767	06-2005	Takai, Mikio	313/311
*	D	US-2003/0049875	03-2003	Sheu et al.	438/20
*	E	US-4,968,585	11-1990	Albrecht et al.	430/320
*	F	US-2003/0102222	06-2003	Zhou et al.	205/109
*	G	US-6,528,785	03-2003	Nakayama et al.	250/306
*	H	US-7,014,743	03-2006	Zhou et al.	204/547
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP 2002-301700 A	10-2002	Japan	Chin et al. (w/ trans)	-
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.